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(54) **OLED LUMINANCE DEGRADATION COMPENSATION**

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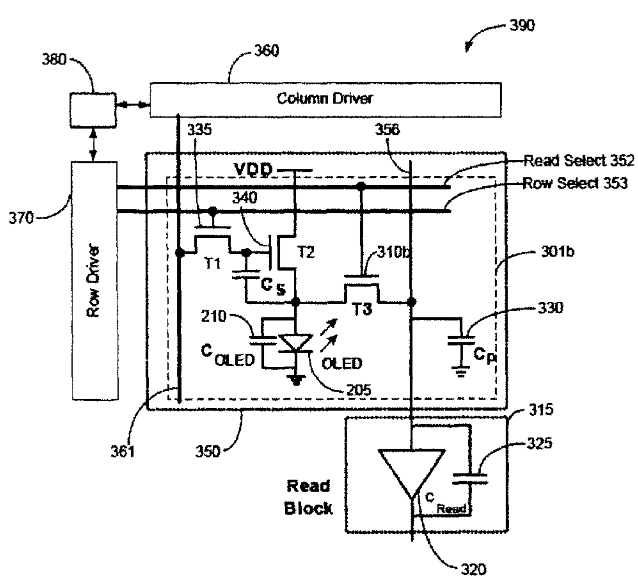
(57) **ABSTRACT**

A system and method are disclosed for determining a pixel capacitance. The pixel capacitance is correlated to a pixel age to determine a current correction factor used for compensating the pixel drive current to account for luminance degradation of the pixel that results from the pixel aging.

17 Claims, 7 Drawing Sheets



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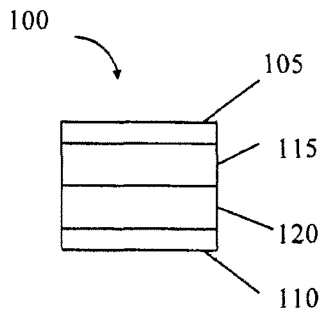


Figure 1

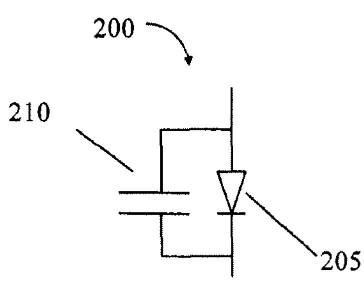
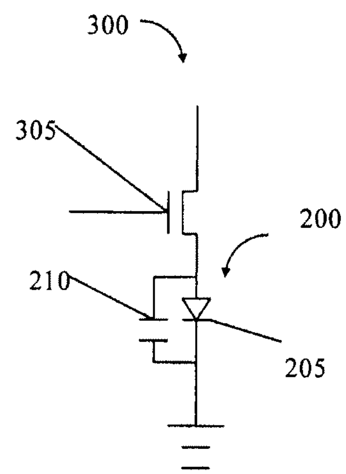


Figure 2



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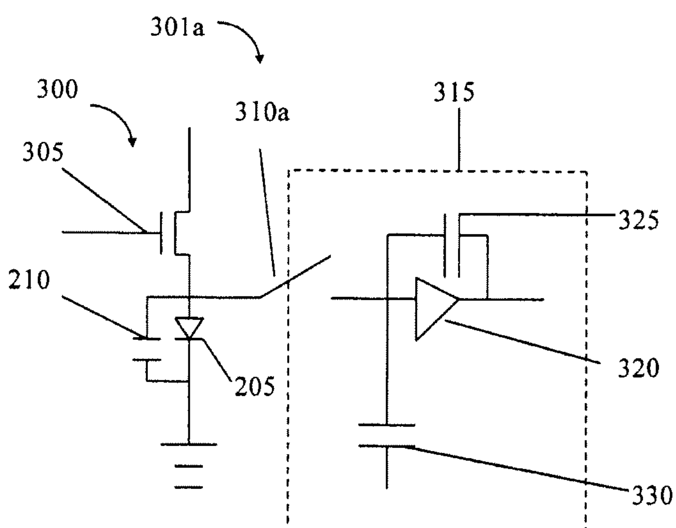
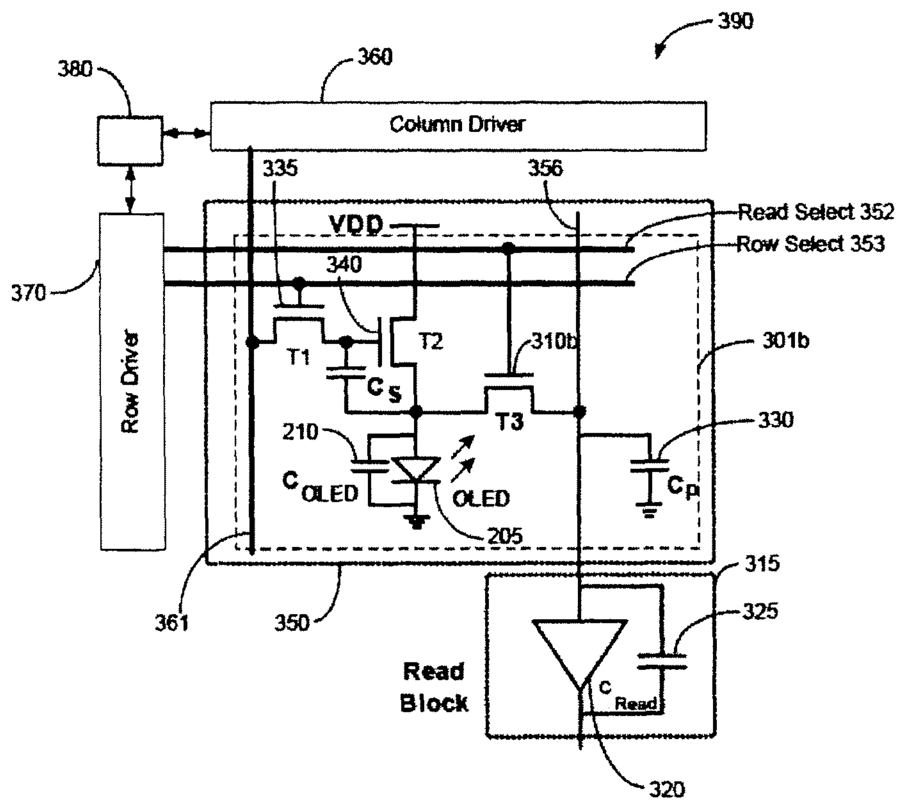


Figure 3b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380
360
Column Driver
335
356
VDD
Read Select 352
Row Select 353
340
370
Row Driver
T1
T2
310b
301b
C_S
T3
210
330
C_{OLED}
OLED
C_p
205
315
361
350
325
Read
Block
C_{Read}
320

Figure 3c

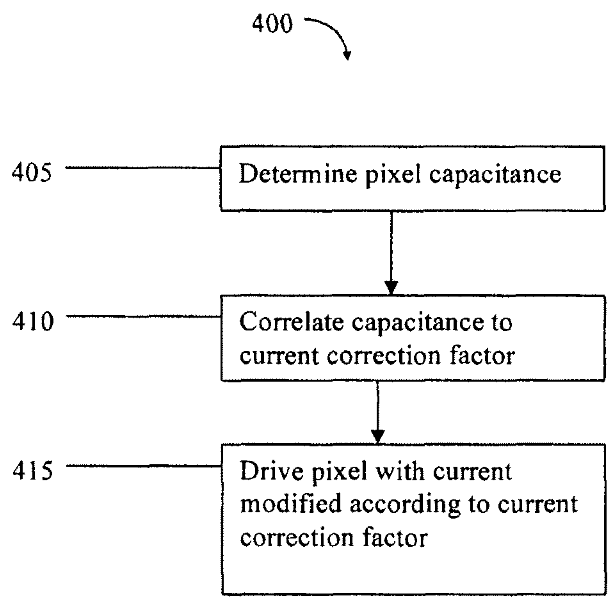


Figure 4

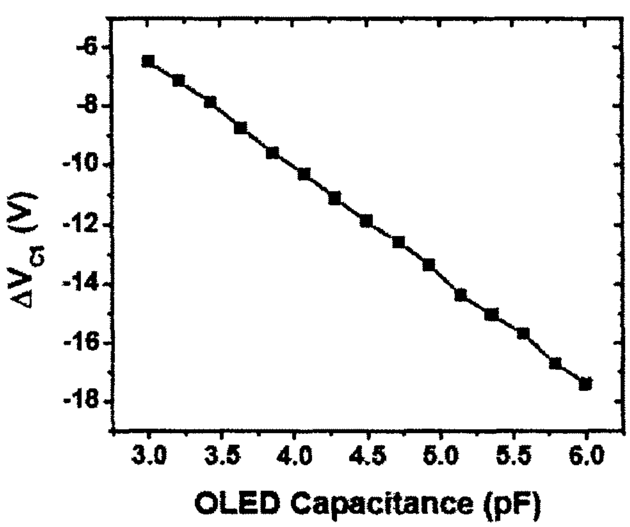


Figure 5

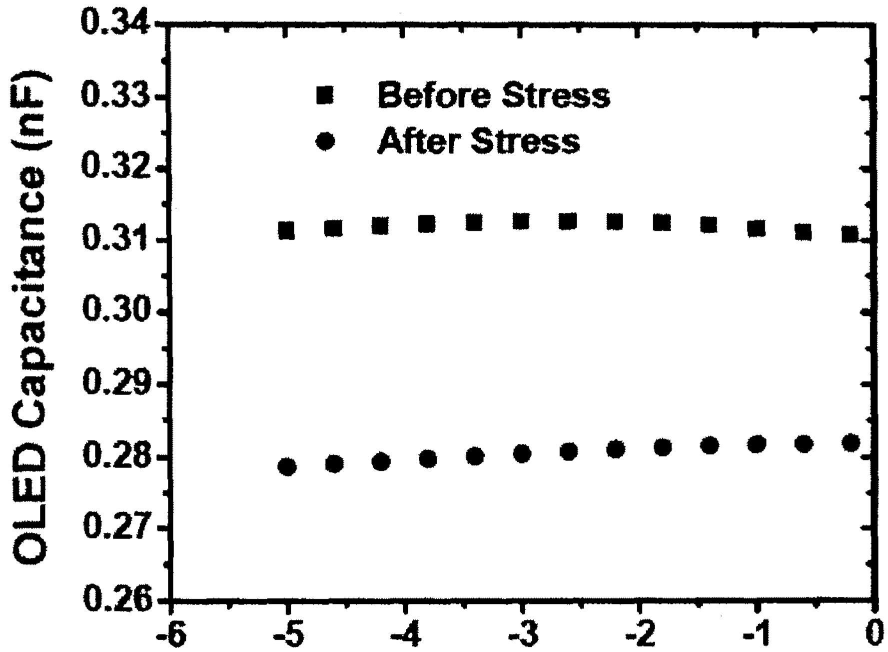


Figure 6

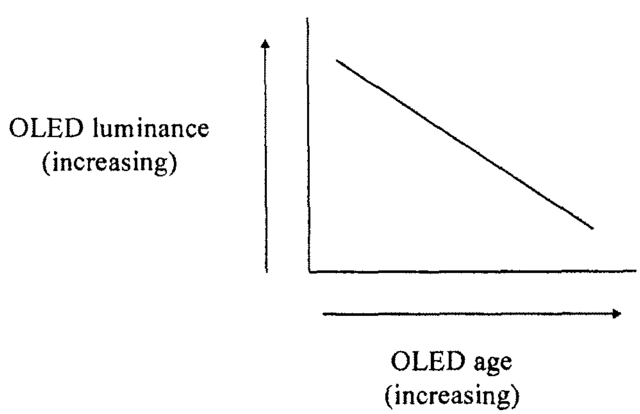
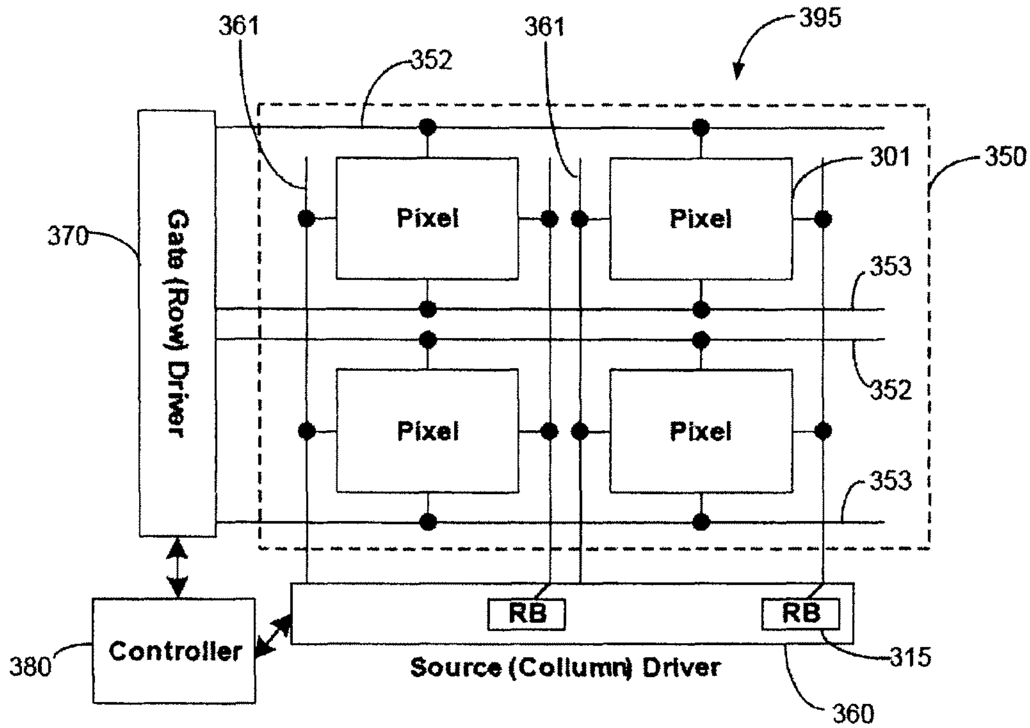


Figure 7



395
361
361
352
301
350
Pixel
Pixel
Pixel
Pixel
370
Gate (Row) Driver
353
352
353
RB
RB
Controller
380
315
Source (Collumn) Driver
360

Figure 8

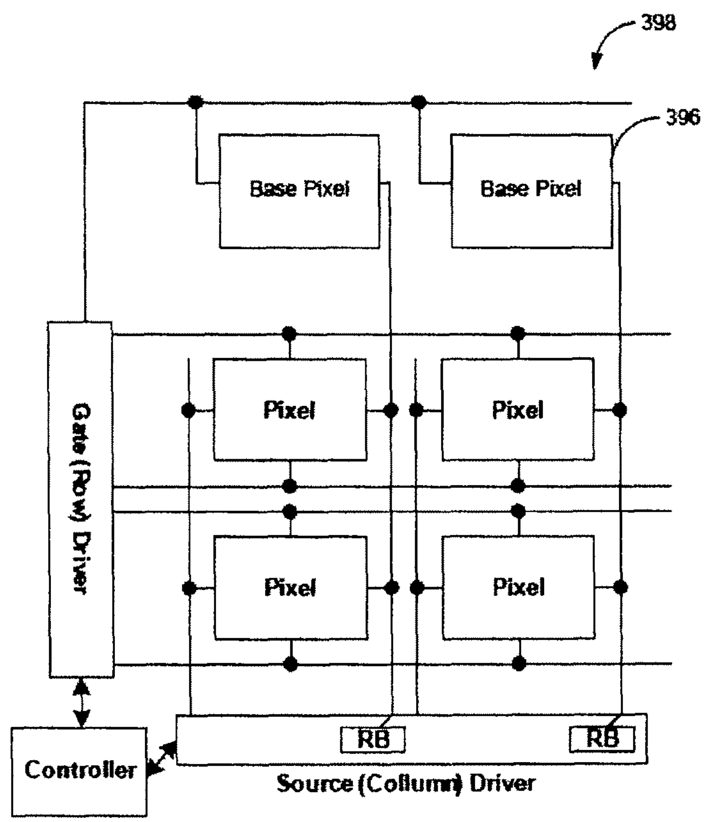

398
396
Base Pixel
Base Pixel
Gate (Row) Driver
Pixel
Pixel
Pixel
Pixel
RB
RB
Controller
Source (Collumn) Driver

Figure 9

OLED LUMINANCE DEGRADATION COMPENSATION

CROSS REFERENCE TO RELATED APPLICATIONS

This application is a continuation of U.S. patent application Ser. No. 13/632,691, filed Oct. 1, 2012, now allowed, which is a continuation of U.S. patent application Ser. No. 13/179,963, filed Jul. 11, 2011, now U.S. Pat. No. 8,279,143, issued Oct. 2, 2012, which is a continuation of U.S. patent application Ser. No. 11/839,145, filed Aug. 15, 2007, now U.S. Pat. No. 8,026,876, issued Sep. 27, 2011, which claims priority to Canadian Patent Application No. 2,556,961, filed Aug. 15, 2006; the entire contents of which are incorporated herein by reference.

FIELD OF THE INVENTION

The present invention relates to OLED displays, and in particular to the compensation of luminance degradation of the OLED based on OLED capacitance.

BACKGROUND

Organic light emitting diodes ("OLEDs") are known to have many desirable qualities for use in displays. For example, they can produce bright displays, they can be manufactured on flexible substrates, they have low power requirements, and they do not require a backlight. OLEDs can be manufactured to emit different colours of light. This makes possible their use in full colour displays. Furthermore, their small size allows for their use in high resolution displays.

The use of OLEDs in displays is currently limited by, among other things, their longevity. As the OLED display is used, the luminance of the display decreases. In order to produce a display that can produce the same quality of display output repeatedly over a period of time (for example, greater then 1000 hours) it is necessary to compensate for this degradation in luminance.

One method of determining the luminance degradation is by measuring it directly. This method measures the luminance of a pixel for a given driving current. This technique requires a portion of each pixel to be covered by the light detector. This results in a lower aperture and resolution.

Another technique is to predict the luminance degradation based on the accumulated drive current applied to the pixel. This technique suffers in that if the information pertaining to the accumulated drive current is lost or corrupted (such as by power failure) the luminance correction cannot be performed.

There is therefore a need for a method and associated system for determining the luminance degradation of an OLED that does not result in a decrease in the aperture ratio, yield or resolution and that does not rely on information about the past operation of the OLED to compensate for the degradation.

SUMMARY

In one embodiment there is provided a method of compensating for luminance degradation of a pixel. The method comprises determining the capacitance of the pixel, and correlating the determined capacitance of the pixel to a current correction factor for the pixel.

In another embodiment there is provided a method of driving a pixel with a current compensated for luminance degradation of the pixel. The method comprises determining the capacitance of the pixel, correlating the determined capacitance of the pixel to a current correction factor for the pixel, compensating a pixel drive current according to the current correction factor, and driving the pixel with the compensated current.

In yet another embodiment there is provided a read block for use in determining a pixel capacitance of a plurality of pixel circuits. The pixel circuits are arranged in an array to form a display. The read block comprises a plurality of read block elements. Each read block element comprises a switch for electrically connecting and disconnecting the read block element to a pixel circuit of the plurality of pixels circuits, an operational amplifier electrically connected to the switch and a read capacitor connected in parallel with the operational amplifier.

In still another embodiment there is provided a display for driving an array of a plurality of pixel circuits with a current compensated for luminance degradation. The display comprises a display panel comprising the array of pixel circuits, the pixel circuits arranged in at least one row and a plurality of columns, a column driver for driving the pixel circuits with a driving current, a read block for determining a pixel capacitance of the pixel circuits, and a control block for controlling the operation of the column driver and the read block, the control block operable to determine a current correction factor from the determined pixel capacitance and to adjust the driving current based on the current correction factor.

BRIEF DESCRIPTION OF THE DRAWINGS

Features and embodiments will be described with reference to the drawings wherein:

FIG. **1** is a block diagram illustrating the structure of an organic light emitting diode;

FIG. **2** is a schematic illustrating a circuit model of an OLED pixel;

FIG. **3***a* is a schematic illustrating a simplified pixel circuit that can be used in a display;

FIG. **3***b* is a schematic illustrating a modified and simplified pixel circuit;

FIG. **3***c* is a schematic illustrating a display, comprising a single pixel;

FIG. **4** is a flow diagram illustrating the steps for driving a pixel with a current compensated to account for the luminance degradation of the pixel;

FIG. **5** is a graph illustrating the simulated change in voltage across the read capacitor using the read block circuit;

FIG. **6** is a graph illustrating the relationship between the capacitance and voltage of a pixel of different ages;

FIG. **7** is a graph illustrating the relationship between the luminance and age of a pixel;

FIG. **8** is a block diagram illustrating a display; and

FIG. **9** is a block diagram illustrating an embodiment of a display.

DETAILED DESCRIPTION

FIG. **1** shows, in a block diagram, the structure of an organic light emitting diode ("OLED") **100**. The OLED **100** may be used as a pixel in a display device. The following description refers to pixels, and will be appreciated that the pixel may be an OLED. The OLED **100** comprises two electrodes, a cathode **105** and an anode **110**. Sandwiched between the two electrodes are two types of organic material. The organic material connected to the cathode **105** is an emissive layer and is typically referred to as a hole transport layer **115**. The organic material connected to the anode **110** is a conductive layer and is typically referred to as an electron transport layer **120**. Holes and electrons may be injected into the organic materials at the electrodes **105**, **110**. The holes and electrons recombine at the junction of the two organic materials **115**, **120** resulting in the emission of light.

The anode **110** may be made of a transparent material such as indium tin oxide. The cathode **105** does not need to be made of a transparent material. It is typically located on the back of the display panel, and may be referred to as the back plane electronics. In addition to the cathode **105**, the back plane electronics may also include transistors and other elements used to control the functioning of the individual pixels.

FIG. **2** shows, in a schematic, a circuit model of an OLED pixel **200**. The pixel may be modeled by an ideal diode **205** connected in parallel with a capacitor **210** having a capacitance C_{oled}. The capacitance is a result of the physical and electrical characteristics of the OLED. When a current passes through the diode **205** (if the diode is an LED) light is emitted. The intensity of the light emitted (the luminance of the pixel) depends on at least the age of the OLED and the current driving the OLED. As OLEDs age, as a result of being driven by a current for periods of time, the amount of current required to produce a given luminance increases.

In order to produce a display that can reproduce an output consistently over a period of time, the amount of driving current necessary to produce a given luminance must be determined. This requires accounting for the luminance degradation resulting from the aging of the pixel. For example, if a display is to produce an output of X cd/m^2 in brightness for 1000 hours, the amount of current required to drive each pixel in the display will increase as the pixels of the display age. The amount that the current must be increased by to produce the given luminance is referred to herein as a current correction factor. The current correction factor may be an absolute amount of current that needs to be added to the signal current in order to provide the compensated driving current to the pixel. Alternatively the current correction factor may be a multiplier. This multiplier may indicate for example that the signal current be doubled to account for the pixel aging. Alternatively the current correction factor may be used in a manner similar to a lookup table to directly correlate a signal current (or desired luminance) with a compensated driving current necessary to produce the desired luminance level in the aged pixel.

As described further herein it is possible to use the change of the pixel's capacitance over time as a feedback signal to stabilize the degradation of the pixel's luminance.

FIG. **3***a* shows, in a schematic, a simplified pixel circuit **300** that can be used for driving a pixel **200**. The transistor **305** acts as a switch for turning on the pixel **200** (shown in FIG. **2**). A driving current passes through the transistor **305** to drive the output of the pixel **200**.

FIG. **3***b* shows, in a schematic, a simplified pixel circuit **301***a*, which has been modified in accordance with methods of present invention. A read block **315** is connected to the pixel circuit **300** of FIG. **3***a* through a switch **310***a*. The read block **315** allows for the capacitance **210** of the pixel **200** to be determined. The read block **315** comprises an op amp **320** connected in parallel with a reading block capacitor **325**. This configuration may be referred to as a charge amplifier. The circuit also has an inherent parasitic capacitance **330**. The circuit elements of the read block **315** may be implemented in the display panel's back plane electronics. Alternatively, the read block elements may be implemented off the display panel. In one embodiment the read block **315** is incorporated into the column driving circuitry of the display.

If the read block **315** circuitry is implemented separately from the back plane circuitry of the display panel, the switch **310***a* may be implemented in the back plane electronics. Alternatively, the switch **310***a* may also be implemented in the separate read block **315**. If the switch **310***a* is implemented in the separate read block **315** it is necessary to provide an electrical connection between the switch **310***a* and the pixel circuit **300**.

FIG. **3***c* shows, in a schematic, a display **390**, comprising a single pixel circuit **301***b* for clarity of the description. The display **390** comprises a row driver **370**, a column driver **360**, a control block **380**, a display panel **350** and a read block **315**. The read block **315** is shown as being a separate component. As previously described, it will be appreciated that the read block circuitry may be incorporated into the other components of the display **390**.

The single transistor **305** controlling the driving of the pixel **200** shown in FIG. **3***b* is replaced with two transistors. The first transistor T**1** **335** acts as a switching transistor controlled by the row drivers **370**. The second transistor T**2** **340** acts as a driving transistor to supply the appropriate current to the pixel **200**. When T**1** **335** is turned on it allows the column drivers **360** to drive the pixel of pixel circuit **301***b* with the drive current (compensated for luminance degradation) through transistor T**2** **340**. The switch **310***a* of FIG. **3***b* has been replaced with a transistor T**3** **310***b*. The control block **380** controls transistor T**3** **310***b*. Transistor T**3** **310***b* may be turned on and off to electrically connect the read block **315** to the pixel circuit.

The Row Select **353** and Read Select **352** lines may be driven by the row driver **370**. The Row Select line **353** controls when a row of pixels is on. The Read Select line **352** controls the switch (transistor T**3**) **310** that connects the read block **315** with the pixel circuit. The Column Driver line **361** is driven by the column driver **360**. The Column Driver line **361** provides the compensated driving current for driving the pixel **200** brightness. The pixel circuit also comprises a Read Block line **356**. The pixel circuit is connected to the Read Block line **356** by the transistor T**3** **310***b*. The Read Block line **356** connects the pixel circuit to the read block **315**.

The control block **380** of the display **390** controls the functioning of the various blocks of the display **390**. The column driver **360** provides a driving current to the pixel **200**. It will be appreciated that the current used to drive the pixel **200** determines the brightness of the pixel **200**. The row drivers **370** determine which row of pixels will be driven by the column drivers **360** at a particular time. The control block **380** coordinates the column **360** and row drivers **370** so that a row of pixels is turned on and driven by an appropriate current at the appropriate time to produce a desired output. By controlling the row **370** and column drivers **360** (for example, when a particular row is turned on and what current drives each pixel in the row) the control block **380** controls the overall functioning of the display panel **350**.

The display **390** of FIG. **3***c* may operate in at least two modes. The first mode is a typical display mode, in which the control block **380** controls the row **370** and column drivers **360** to drive the pixels **200** for displaying an appropriate output. In the display mode the read block **315** is not electrically connected to the pixel circuits as the control block **380** controls transistor T**3** **310***b* so that the transistor T**3** **310***b* is off. The second mode is a read mode, in which the control block **380** also controls the read block **315** to determine the capacitance of the pixel **200**. In the read mode, the control block **380** turns on and off transistor T**3** **310***b* as required.

FIG. **4** shows, in a flow diagram **400**, the steps for driving a pixel with a current compensated to account for the luminance degradation of the pixel. The capacitance of the pixel is determined in step **405**. The determined capacitance is then correlated to a current correction factor in step **410**. This correlation may be done in various ways, such as through the solving of equations modeling the aging of the pixel type, or through a lookup means for directly correlating a capacitance to a current correction factor in step **415**.

When determining the capacitance of a pixel of a display as shown in FIG. **3***c*, the switch is initially closed (transistor T**3** **310***b* is on), electrically connecting the pixel circuit to the read block **315** through the Read Block line **356**, and the capacitance **210** of the pixel is charged to an initial voltage V**1** determined by the bias voltage of the read block **315** (e.g. charge amplifier). The switch is then opened (transistor T**3** is turned off), disconnecting the pixel circuit from the Read Block line **356** and in turn the read block **315**. The parasitic capacitance **330** of the read block **315** (or Read Block line **356**) is then charged to another voltage V**2**, determined by the bias voltage of the read block **315** (e.g. charge amplifier). The bias voltage of read block **315** (e.g. charge amplifier) is controlled by the control block **380**, and may therefore be different from the voltage used to charge the pixel capacitance **210**. Finally, the switch is closed again, electrically connecting the read block **315** to the pixel circuit. The pixel capacitance **210** is then charged to V**2**. The amount of charge required to change the voltage at Cored from V**1** to V**2** is stored in the read capacitor **325** which can be read as a voltage.

The accuracy of the method may be increased by waiting for a few micro seconds between the time the parasitic capacitance **330** is charged to voltage V**2** and when the switch **310** is closed to electrically connect the read block **315** to the pixel circuit. In the few microseconds the leakage current of the read capacitor **315** can be measured, a resultant voltage determined and deducted from the final voltage seen across the read capacitor **315**.

The change in voltage across the read capacitor **315** is measured once the switch **310** is closed. Once the pixel capacitance **210** and the parasitic capacitance **330** are charged to the same voltage, the voltage change across the read capacitor **325** may be used to determine the capacitance **210** of the pixel **200**. The voltage change across the read capacitor **325** changes according to the following equation:

where

$$\Delta Vc_{read} = -\frac{C_{oled}}{C_{read}}(V1 - V2)$$

ΔV_{Cread} is the voltage change across the read capacitor **325** from when the switch **310** is closed, connecting the charged parasitic **330** and pixel capacitances **210**, to when the voltage across the two capacitances is equal;

C_{oled} is the capacitance **210** of the pixel (in this case an OLED);

C_{read} is the capacitance of the read capacitor **325**;

V**1** is the voltage that the pixel capacitance **210** is initially charged to; and

V**2** is the voltage that the parasitic capacitance **330** is charged to once the switch is opened.

The voltages V**1** and V**2** will be known and may be controlled by the control block **380**. C_{read} is known and may be selected as required to meet specific circuit design requirements. ΔC_{read} is measured from the output of the op amp **320**. From the above equation, it is clear that as C_{oled} decreases, ΔVC_{read} decreases as well. Furthermore the gain is determined by V**1**, V**2** and C_{read}. The values of V**1** and V**2** may be controlled by the control block **380** (or wherever the circuit is that controls the voltage). It will be appreciated that the measurement may be made by converting the analog signal of the op amp **320** into a digital signal using techniques known by those skilled in the art.

FIG. **5** shows, in a graph, the simulated change in voltage across the read capacitor **325** using the read block **315** circuit described above. From the graph it is apparent that the read block **315** may be used to determine the capacitance **210** of the pixel **200** based on the measured voltage change across the read capacitor **325**.

Once the capacitance **210** of the pixel **200** is determined it may be used to determine the age of the pixel **200**. As previously described, the relationship between the capacitance **210** and age of a pixel **200** may be determined experimentally for different pixel types by stressing the pixels with a given current and measuring the capacitance of the pixel periodically. The particular relationship between the capacitance and age of a pixel will vary for different pixel types and sizes and can be determined experimentally to ensure an appropriate correlation can be made between the capacitance and the age of the pixel.

The read block **315** may contain circuitry to determine the capacitance **210** of the pixel **200** from the output of the operational amplifier **320**. This information would then be provided to the control block **380** for determining the current correction factor of the pixel **200**. Alternatively, the output of the operational amplifier **320** of the read block **315** may be provided back to the control block **380**. In this case, the control block **380** would comprise the circuitry and logic necessary to determine the capacitance **210** of the pixel **200** and the resultant current correction factor.

FIG. **6** shows, in a graph, the relationship between the capacitance and voltage of a pixel before and after aging. The aging was caused by stressing the pixel with a constant current of 20 mA/cm^2 for a week. The capacitance may be linearly related to the age. Other relationships are also possible, such as a polynomial relationship. Additionally, the relationship may only be able to be represented correctly by experimental measurements. In this case additional measurements are required to ensure that the modeling of the capacitance-age characteristics are accurate.

FIG. **7** shows, in a graph, the relationship between the luminance and age of a pixel. This relationship may be determined experimentally when determining the capacitance of the pixel. The relationship between the age of the pixel and the current required to produce a given luminance may also be determined experimentally. The determined relationship between the age of the pixel and the current required to produce a given luminance may then be used to compensate for the aging of the pixel in the display.

A current correction factor may be used to determine the appropriate current at which to drive a pixel in order to produce the desired luminance. For example, it may be determined experimentally that in order to produce the same luminance in a pixel that has been aged (for example by driving it with a current of 15 mA/cm^2 for two weeks) as that of a new pixel, the aged pixel must be driven with 1.5 times the current. It is possible to determine the current required for a given luminance at two different ages, and assume that the aging is a linear relationship. From this, the current correction factor may be extrapolated for different ages. Furthermore, it may be assumed that the current correction factor is the same at different luminance levels for a pixel of a given age. That is, in order to produce a luminance of X cd/m^2 requires a current correction factor of 1.1 and that in order to produce a luminance of 2X cd/m^2 also requires a current correction factor of

1.1 for a pixel of a given age. Making these assumptions reduces the amount of measurements that are required to be determined experimentally.

Additional information may be determined experimentally, which results in not having to rely on as many assumptions. For example the pixel capacitance **210** may be determined at four different pixel ages (it is understood that the capacitance could be determined at as many ages as required to give the appropriate accuracy). The aging process may then be modeled more accurately, and as a result the extrapolated age may be more accurate. Additionally, the current correction factor for a pixel of a given age may be determined for different luminance levels. Again, the additional measurements make the modeling of the aging and current correction factor more accurate.

It will be appreciated that the amount of information obtained experimentally may be a trade off between the time necessary to make the measurements, and the additional accuracy the measurements provide.

FIG. **8** shows, in a block diagram, a display **395**. The display **395** comprises a display panel **350**, a row driver block **370**, a column driver block **360** and a control block **380**. The display panel **350** comprises an array of pixel circuits **301***b* arranged in row and columns. The pixel circuits **301***a* of the display panel **350** depicted in FIG. **8** are implemented as shown in FIG. **3***c*, and described above. In the typical display mode, transistor T**3** **310***b* is off and the control block **380** controls the row driver **360** so that the Read Select line **352** is driven so as to turn off transistor T**3** **310***b*. The control block **380** controls the row driver **370** so that the row driver **370** drives the Row Select line **353** of the appropriate row so as to turn on the pixel row. The control block **380** then controls the column drivers **360** so that the appropriate current is driven on the Column Drive line **361** of the pixel. The control block **380** may refresh each row of the display panel **350** periodically, for example 60 times per second.

When the display **395** is in the read mode, the control block **380** controls the row driver **370** so that it drives the Read Select line **352** (for turning on and off the switch, transistor T**3** **310**) and the bias voltage of the read block **315** (and so the voltage of the Read Block line **356**) for charging the capacitances to V**1** and V**2** as required to determine the capacitance **210** of the pixel **200**, as described above. The control block **380** performs a read operation to determine the capacitance **210** of each pixel **200** of a pixel circuit **301***b* in a particular row. The control block then uses this information to determine the age of the pixel, and in turn a current correction factor that is to be applied to the driving current.

In addition to the logic for controlling the drivers **360**, **370** and read block **315**, the control block **380** also comprises logic for determining the current correction factor based on the capacitance **210** as determined with the read block **315**. As described above, the current correction factor may be determined using different techniques. For example, if the pixel is measured to determine its initial capacitance and its capacitance after aging for a week, the control block **380** can be adapted to determine the age of a particular capacitance by solving a linear equation defined by the two measured capacitances and ages. If the required current correction factor is measured for a single luminance at each level, than the current correction factor can be determined for a pixel using a look-up table that gives the current correction factor for a particular pixel age. The control block **380** may receive a pixel's capacitance **210** from the read block **315** and determine the pixel's age by solving a linear equation defined by the two measured capacitances for the different ages of the pixel. From the determined age the control block **315** determines a current correction factor for the pixel using a look-up table.

If additional measurements of the pixel aging process were taken, then determining the age of the pixel may not be as simple as solving a linear equation. For example if three points P**1**, P**2** and P**3** are taken during the aging process such that the aging is linear between the points P**1** and P**2**, but is exponential or non-linear between points P**2** and P**3**, determining the age of the pixel may require first determining what range the capacitance is in (i.e. between P**1**-P**2**, or P**2**-P**3**) and then determining the age as appropriate.

The method used by the control block **380** for determining the age of a pixel may vary depending on the requirements of the display. How the control block **380** determines the pixel age and the information required to do so would be programmed into the logic of the control block. The required logic may be implemented in hardware, such as an ASIC (Application Specific Integrated Circuit), in which case it may be more difficult to change how the control block **380** determines the pixel age. The required logic could be implemented in a combination of hardware and software so that it is easier to modify how the control block **380** determines the age of the pixel.

In addition to the various ways to correlate the capacitance to age, the control block **380** may determine the current correction factor in various ways. As previously described, current correction factors may be determined for various luminance levels. Like with the age-capacitance correlation, the current correction factor for a particular luminance level may be extrapolated from the available measurements. Similar to the capacitance-age correlation, the specifics on how the control block **380** determines the current correction factor can vary, and the logic required to determine the current correction factor can be programmed into the control block **380** in either hardware or software

Once a current correction factor is determined for a pixel, it is used to scale the driving current as required.

FIG. **9** shows in a block diagram an embodiment of a display **398**. The display **390** described above, with reference to FIG. **8**, may be modified to correct for pixel characteristics common to the pixel type. For example, it is known that the characteristics of pixels depend on the temperature of the operating environment. In order to determine the capacitance that is the result of aging, the display **398** is provided with an additional row of pixels **396**. These pixels **396**, referred to as base pixels, are not driven by display currents, as a result they do not experience the aging that the display pixels experience. The base pixels **396** may be connected to the read block **315** for determining their capacitance. Instead of using the pixel capacitance directly, the control block **380** may then use the difference between the pixel capacitance **210** and the base capacitance as the capacitance to use when determining the age of the display pixel.

This provides the ability to easily combine different corrections together. Since the age of the pixel was determined based on a capacitance corrected to account for the base pixel capacitance, the age correction factor does not include correction for non-aging factors. For example, a current correction factor may be determined that is the sum of two current correction factors. The first may be the age-related current correction factor described above. The second may be an operating environment temperature related correction factor.

The control block **380** may perform a read operation (i.e. operate in the read mode) at various frequencies. For example, a read operation may be performed every time a frame of the display is refreshed. It will be appreciated that the time required to perform a read operation is determined by the components. For example, the settling time required for the capacitances to be charged to the desired voltage depends on the size of the capacitors. If the time is large relative to the frame refresh rate of the display, it may not be possible to perform a read each time the frame is refreshed. In this case the control block may perform a read, for example, when the display is turned on or off. If the read time is comparable to the refresh rate it may be possible to perform a read operation once a second. This may insert a blank frame into the display once every **60** frames. However, this may not degrade the display quality. The frequency of the read operations is dependent upon at least the components that make up the display and the required display characteristics (for example frame rate). If the read time is short compared to the refresh rate, a read may be performed prior to driving the pixel in the display mode.

The read block **315** has been described above as determining the capacitance **210** of a single pixel **200** in a row. A single read block **315** can be modified to determine the capacitance of multiple pixels in a row. This can be accomplished by including a switch (not shown) to determine what pixel circuit **301***b* the read block **315** is connected to. The switch may be controlled by the control block **380**. Furthermore, although a single read block **315** has been described, it is possible to have multiple read blocks for a single display. If multiple read blocks are used, then the individual read blocks may be referred to as read block elements, and the group of multiple read block elements may be referred to as a read block.

Although the above description describes a circuit for determining the capacitance **210** of a pixel **200**, it will be appreciated that other circuits or methods could be used for determining the pixel capacitance **210**. For example in place of the voltage amplifier configuration of the read block **315**, a transresistance amplifier may be used to determine the capacitance of the pixel. In this case the capacitance of the pixel and the parasitic capacitance is charged using a varying voltage signal, such as a ramp or sinusoidal signal. The resultant current can be measured and the capacitance determined. Since the capacitance is a combination of the parasitic capacitance **330** and the pixel capacitance **210**, the parasitic capacitance **330** must be known in order to determine the pixel capacitance **210**. The parasitic capacitance **330** may be determined by direct measurement. Alternatively or additionally the parasitic capacitance **330** may be determined using the transresistance amplifier configuration read block. A switch may disconnect the pixel circuit from the read block. The parasitic capacitance **330** would then be determined by charging it with a varying voltage signal and measuring the resultant current.

The embodiments described herein for compensating for the luminance degradation of pixels due to electrical aging can be advantageously included in a display panel without decreasing the yield, aperture ratio or resolution of the display. The electronics required to implement the technique can easily be included in the electronics required by the display without significantly increasing the display size or power requirements.

One or more currently illustrated embodiments have been described by way of example. It will be apparent to persons skilled in the art that a number of variations and modifications can be made without departing from the scope of the invention as defined in the claims.

What is claimed is:

1. A method of compensating for luminance degradation of a pixel having a luminescent device, the method comprising:
determining a luminance degradation resulting from aging of the pixel;
determining based on the determined luminance degradation a current correction factor;
compensating a drive current for the luminescent device based on the current correction factor; and
driving the luminescent device with the compensated drive current.

2. The method of claim **1**, wherein the current correlation factor is an absolute amount of current to be added to the drive current.

3. The method of claim **1**, wherein the current correction factor is a multiplier by which the drive current is multiplied in connection with the compensating.

4. The method of claim **1**, wherein the current correction factor is retrieved from a lookup table that correlates desired luminance values with compensated driving currents, the lookup table being stored in a memory device.

5. The method of claim **1**, wherein the luminance degradation is determined by a read block connected to the pixel by a switch, the read block reading a characteristic of the pixel or of the luminescent device when the switch is closed.

6. The method of claim **5**, wherein the characteristic is a capacitance.

7. The method of claim **5**, further comprising deducting a voltage caused by a leakage current caused by the read block so that the current correction factor is not influenced by the leakage current.

8. The method of claim **1**, wherein the current correction factor is determined based on a plurality of current correction factors, wherein a first of the current correction factors is an age-related current correction factor related to the aging of the pixel and another of the current correction factors is a temperature-related correction factor relating to an environmental temperature.

9. A method of compensating a drive current of a pixel, the method comprising:
determining a combined correction factor that is based on an age-related correction factor and a non-age-related correction factor;
compensating a drive current for the pixel based on the combined correction factor; and
driving the pixel with the compensated drive current.

10. The method of claim **9**, where the combined correction factor is a sum of the age-related correction factor and the non-age-related correction factor, the non-age-related correction factor being a temperature-related correction factor.

11. The method of claim **10**, further comprising:
prior to the determining the combined correction factor, determining a luminance degradation of the pixel resulting from aging of the pixel;
determining, based on the determined luminance degradation, the age-related correction factor; and
determining, based on an operating environment temperature, the temperature-related correction factor.

12. The method of claim **11**, wherein the pixel is an organic light emitting diode (OLED).

13. The method of claim **12**, wherein the determining the luminance degradation of the pixel includes determining a capacitance of the OLED.

14. The method of claim **11**, wherein the pixel is one of a plurality of pixels arranged in an array to form a display device.

15. The method of claim **11**, further comprising updating the determined luminance degradation of the pixel more than once during a lifetime of the pixel so as to account for ongoing aging degradation during the lifetime of the pixel.

16. The method of claim 14, further comprising:

determining a capacitance of the pixel during a read operation of the display device, the pixel having been aged by use of the pixel to selectively emit light during a display operation of the display device;

determining a capacitance of a base pixel of the display during the read operation, the base pixel not having been used to selectively emit light during the display operation; and

the determining the luminance degradation of the pixel resulting from aging of the pixel comprises using a difference between the determined capacitance of the pixel and the determined capacitance of the base pixel.

17. The method of claim 16, wherein the pixel is an organic light emitting diode (OLED).

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